

# **TEST REPORT**

Product Name: Intelligent Processing Card

Trade Mark: Cambricon
Model No.: MLU270-X5K

Add. Model No.: MLU270-X5, MLU270-XV5K

Report Number: 200110005EMC-1

Test Standards: FCC 47 CFR Part 15 Subpart B

ICES-003 Issue 6

FCC ID: 2ARVF-MLU270-X

Test Result: PASS

Date of Issue: February 28, 2020

#### Prepared for:

Cambricon Technologies Corporation Limited
Room 1805, Building 1, Lane 2290, Zuchongzhi Road, Zhangjiang HiTech Park, Shanghai, China

#### Prepared by:

Shenzhen UnionTrust Quality and Technology Co., Ltd.

16/F, Block A, Building 6, Baoneng Science and Technology Park,
Qingxiang Road No.1, Longhua New District, Shenzhen, China

TEL: +86-755-2823 0888 FAX: +86-755-2823 0886

Prepared by:

Eric Yu

Team Leade

Reviewed by:

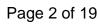
Kevin Liang Assistant Manager

Approved by:

Date:

February 28, 2020

**Technical Director** 





**Version** 

Version No. Date		Description
V1.0	February 28, 2020	Original





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# 1. GENERAL INFORMATION

## 1.1 CLIENT INFORMATION

Applicant:	Cambricon Technologies Corporation Limited
Address of Applicant:	Room 1805, Building 1, Lane 2290, Zuchongzhi Road, Zhangjiang Hi-Tech Park, Shanghai, China
Manufacturer:	Cambricon Technologies Corporation Limited
Address of Manufacturer:	Room 1805, Building 1, Lane 2290, Zuchongzhi Road, Zhangjiang Hi-Tech Park, Shanghai, China

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## 1.2 EUT INFORMATION

## 1.2.1 General Description of EUT

Product Name:	Intelligent Processing Card		
Model No.:	MLU270-X5K		
Add. Model No.:	MLU270-X5, MLU270-XV5K		
Trade Mark: Cambricon			
DUT Stage:	Production Unit		
Rated Voltage:	12.0 V == 7.5 A		
Classification of digital devices:	Class B		
Highest Internal Frequency:	1.25 GHz		
Software Version:	V1.1.3		
Hardware Version:	V1.2		
Sample Received Date:	January 13, 2020		
Sample Tested Date:	January 15, 2020 to February 27, 2020		

**Note:** The model of MLU270-X series Intelligent Processing Card description MLU270-X series are Intelligent Processing Card, the layout of PCB in the MLU270-X series are same, and the size are same too.

They contain three models, and the differences are as follows:

MLU270-X5		MLU270-X5K	MLU270-XV5K	
IDII	C20L	C20L	C20L	
IPU	Support max 1.0GHz	Support max 1.25GHz	Support max 1. 25GHz	
Hashrate	INT8 128TOPS	INT8 160T0PS	INT8 160TOPS	
Appearance	Silver and Blue	Silver and Blue	Silver	

## 1.2.2 Description of Accessories

None

## 1.3 DESCRIPTION OF SUPPORT UNITS

The EUT has been tested with associated equipment below.

1) Support Equipment

Description	Manufacturer	Model No.	Serial Number	Supplied by
Computer host	DELL	Precision Tower 5820	NA	Applicant
LED Monitor	LG	U320S	187A3028-00001D	Union Trust



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Mouse	DELL	MOCZUL	CN-0V7623-73826- 65K-00XR	Union Trust
Keyboard	DELL	KB216t	CN-0RKR0N- 71616-66O-0U4V- A03	Union Trust

#### 2) Support Cable

Description Quantity		Cable Type	Length (m)	Supplied by
Power Cable	1	Unshielded without ferrite	1.50	UnionTrust
HDMI Cable	1	Unshielded without ferrite	1.50	UnionTrust

#### 1.4 TEST LOCATION

#### Shenzhen UnionTrust Quality and Technology Co., Ltd.

Address: 16/F, Block A, Building 6, Baoneng Science and Technology Park, Qingxiang Road No.1, Longhua

New District, Shenzhen, China 518109 Telephone: +86 (0) 755 2823 0888 Fax: +86 (0) 755 2823 0886

#### 1.5 TEST FACILITY

The test facility is recognized, certified, or accredited by the following organizations:

#### CNAS-Lab Code: L9069

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable under the ISO/IEC/EN 17025 to international or national standards. Equipment has been calibrated by accredited calibration laboratories.

#### A2LA-Lab Certificate No.: 4312.01

Shenzhen UnionTrust Quality and Technology Co., Ltd. has been accredited by A2LA for technical competence in the field of electrical testing, and proved to be in compliance with ISO/IEC 17025: 2005 General Requirements for the Competence of Testing and Calibration Laboratories and any additional program requirements in the identified field of testing.

### ISED Wireless Device Testing Laboratories

CAB identifier: CN0032

#### FCC Accredited Lab.

Designation Number: CN1194

Test Firm Registration Number: 259480

## 1.6 DEVIATION FROM STANDARDS

None.

#### 1.7 ABNORMALITIES FROM STANDARD CONDITIONS

None.

#### Shenzhen UnionTrust Quality and Technology Co., Ltd.



## 1.8 OTHER INFORMATION REQUESTED BY THE CUSTOMER

None.

## 1.9 MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

No.	Item	Measurement Uncertainty		
1	Conducted emission 9KHz-150KHz	±3.8 dB		
2	Conducted emission 150KHz-30MHz	±3.4 dB		
3	Radiated emission 9KHz-30MHz	±4.9 dB		
4	Radiated emission 30MHz-1GHz	±4.7 dB		
5	Radiated emission 1GHz-18GHz	±5.1 dB		
6	Radiated emission 18GHz-26GHz	±5.2 dB		
7	Radiated emission 26GHz-40GHz	±5.2 dB		

## 2. TEST SUMMARY

FCC 47 CFR Part 15 Subpart B Test Cases							
Test Item Test Requirement Test Method Result							
Conducted Emission	FCC 47 CFR Part 15.107 ICES-003 Issue 6 Section 6.1	ANSI C63.4-2014	PASS				
Radiated Emission	FCC 47 CFR Part 15.109 ICES-003 Issue 6 Section 6.2	ANSI C63.4-2014	PASS				



## 3. EQUIPMENT LIST

	Radiated Emission Test Equipment List							
Used	Equipment	Manufacturer	Model No.	Serial Number	Cal. date (mm dd, yyyy)	Cal. Due date (mm dd, yyyy)		
$\boxtimes$	3M Chamber & Accessory Equipment	ETS-LINDGREN	3M	N/A	Dec. 03, 2018	Dec. 03, 2021		
$\boxtimes$	Receiver	R&S	ESIB26	100114	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	Broadband Antenna	ETS-LINDGREN	3142E	00201566	Nov. 16, 2019	Nov. 15, 2020		
$\boxtimes$	6dB Attenuator	Talent	RA6A5-N- 18	18103001	Nov. 16, 2019	Nov. 15, 2020		
$\boxtimes$	Preamplifier	HP	8447F	2805A02960	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	Horn Antenna (Pre-amplifier)	ETS-LINDGREN	3117-PA	00201874	May 18, 2019	May 18, 2020		
$\boxtimes$	Multi device Controller	ETS-LINDGREN	7006-001	00160105	N/A	N/A		
$\boxtimes$	Test Software	Audix	e3	Software Version: 9.160323				

	Conducted Emission Test Equipment List							
Used	Equipment	Manufacturer	Model No.	Serial Number	Cal. date (mm dd, yyyy)	Cal. Due date (mm dd, yyyy)		
$\boxtimes$	Receiver	R&S	ESR7	1316.3003K07 -101181-K3	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	Pulse Limiter	R&S	ESH3-Z2	0357.8810.54	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	LISN	R&S	ESH2-Z5	860014/024	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	LISN	ETS-Lindgren	3816/2SH	00201088	Nov. 24, 2019	Nov. 23, 2020		
$\boxtimes$	Test Software	Audix	e3	Sof	tware Version: 9.160323			



## 4. TEST CONFIGURATION

## 4.1 ENVIRONMENTAL CONDITIONS FOR TESTING

## 4.1.1 Normal or Extreme Test Conditions

<b>Environment Parameter</b>	Selected Values During Tests		
Test Condition	Ambient		
rest Condition	Temperature (°C)	Voltage (V)	Relative Humidity (%)
NT/NV	+15 to +35	AC120/60Hz&AC240/50Hz	20 to 75
Remark: 1) NV: Normal Voltage; NT: Normal Temperature			

#### 4.1.2 Record of Normal Environment

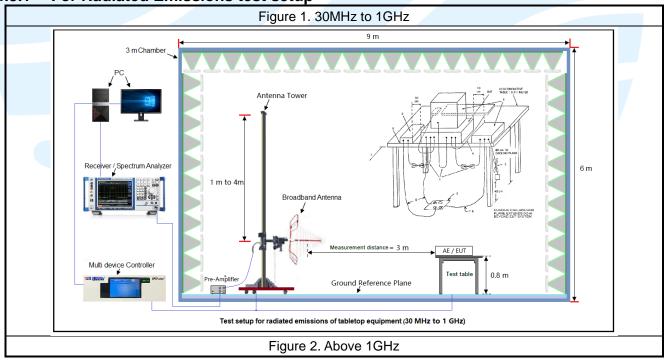
Test Item	Temperature (°C)	Relative Humidity (%)	Pressure (kPa)	Tested by
Conducted Emission	25.5	32.0	100.2	Andy Lin
Radiated Emission	25.3	53.0	100.1	Andy Lin

## **4.2 TEST MODES**

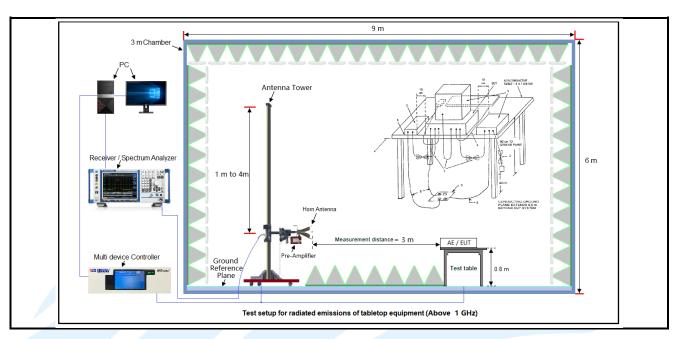
Test Item	EMI Test Modes	
Radiated Emission	TM1: Data processing(AC120V/60Hz) TM2: Data processing(AC240V/50Hz)	
Conducted Emission	TM1: Data processing(AC120V/60Hz) TM2: Data processing(AC240V/50Hz)	

## **4.3 TEST SETUP**

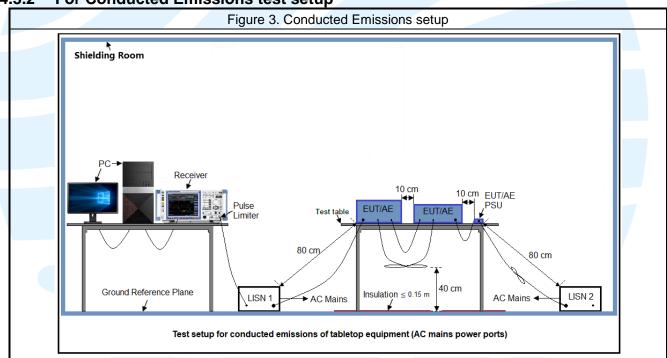
## 4.3.1 For Radiated Emissions test setup







4.3.2 For Conducted Emissions test setup



## 4.4 SYSTEM TEST CONFIGURATION

All readings are extrapolated back to the equivalent three meter reading using inverse scaling with distance. Analyzer resolution is 100 kHz or greater for frequencies below 1000MHz. The resolution is 1 MHz or greater for frequencies above 1000MHz. The spurious emissions more than 20 dB below the permissible value are not reported.

Radiated emission measurement were performed from the lowest radio frequency signal generated in the device which is greater than 9 kHz to the tenth harmonic (according to KDB 896810 D02 SDoC FAQ v01r01) of the highest fundamental frequency or to 40 GHz, whichever is lower.

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## 5. REFERENCE DOCUMENTS FOR TESTING

No.	Identity	Document Title			
1	FCC 47 CFR Part15 Subpart B	Unintentional Radiators			
2	ICES-003 Issue 6	Information Technology Equipment (Including Digital Apparatus) — Limits and Methods of Measurement			
3	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz			
4	KDB 174176 D01 Line	AC power-line conducted emission frequency asked questions			
	Conducted FAQ v01r01				
5	KDB 896810 D02 SDoC FAQ v01r02	Supplier's Declaration of Conformity frequency asked questions			

# 6. EMC REQUIREMENTS SPECIFICATION 6.1 RADIATED EMISSION

**Test Requirement:** FCC 47 CFR Part 15.109 ICES-003 Issue 6 Clause 6.2

Test Method: ANSI C63.4-2014

**Receiver Setup:** 

	Frequency: (f)	Frequency: (f)  Detector type  Measurement receiver bandwidth		ceiver bandwidth
	(MHz)	Detector type	RBW	VBW
	$30 \le f \le 1000$	Quasi Peak	120 kHz	300 kHz
	f ≥1000	Peak	1 MHz	3 MHz
		Average	1 MHz	3 MHz

#### Measured frequency range

Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)	
Below 1.705	30.	
1.705-108	1000.	
108-500	2000.	
500-1000	5000.	
Above 1000	5th harmonic of the highest frequency or 40 GHz, whichever is lower.	

#### Limits:

Limits for Class B devices

Fraguency (MHz)	limits at 3m (dBμV/m)		
Frequency (MHz)	QP Detector	PK Detector	AV Detector
30-88	40.0		
88-216	43.5		
216-960	46.0		
960 to 1000	54.0		
Above 1000		74.0	54.0

#### Remark:

- 1. The lower limit shall apply at the transition frequencies.
- 2. Emission level  $(dB\mu V/m) = 20 \log Emission level (\mu V/m)$ .
- 3. For frequencies above 1000 MHz, the field strength limits are based on average detector, however, the peak field strength of any emission shall not exceed the maximum permitted average limits, specified above by more than 20 dB under any condition of modulation.

### Shenzhen UnionTrust Quality and Technology Co., Ltd.



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**Test Setup:** Refer to section 4.3.1 for details.

#### **Test Procedures:**

- 1. From 30 MHz to 1GHz test procedure as below:
- 1) The Product was placed on the non-conductive turntable 0.8 m above the ground at a chamber.
- 2) Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- 3) For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.
- 2. Above 1GHz test procedure as below:
- 1) The Product was placed on the non-conductive turntable 0.8 m above the ground at a chamber.
- 2) Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 1MHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- 3) For each frequency whose maximum record was higher or close to limit, measure its AV value: rotate the turntable from 0 to 360 degrees to find the degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to AV value and specified bandwidth with Maximum Hold Mode, and record the maximum value.

**Equipment Used:** Refer to section 3 for details.

Test Result: Pass



6

938.714

30.94

5.73

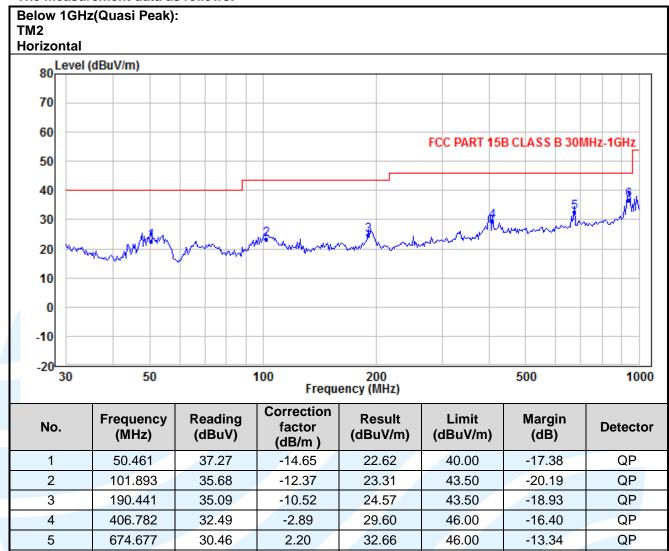
36.67

46.00

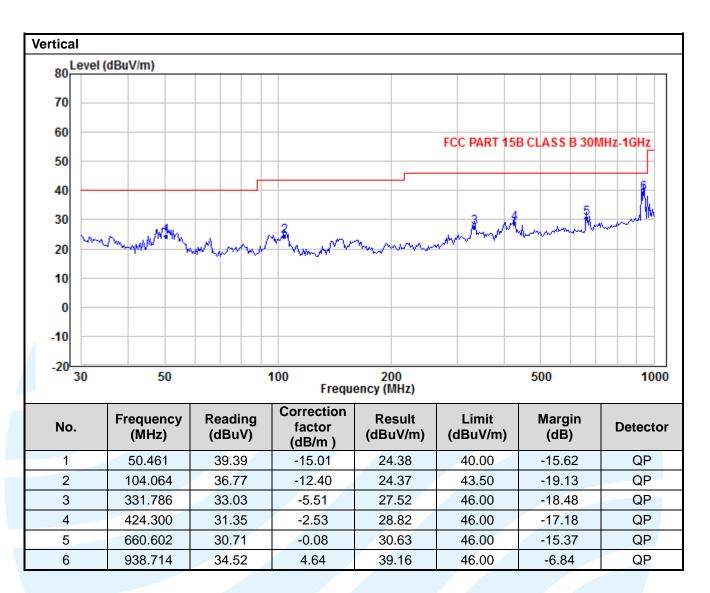
-9.33

QP

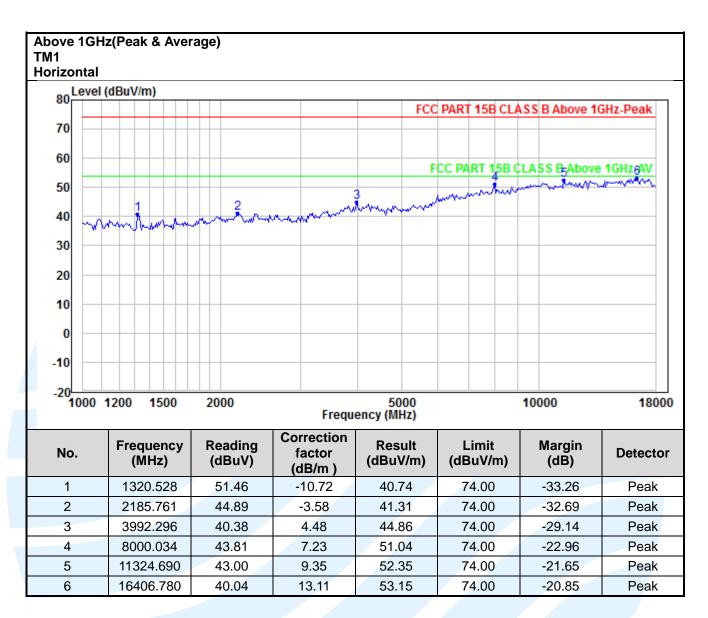
#### The measurement data as follows:



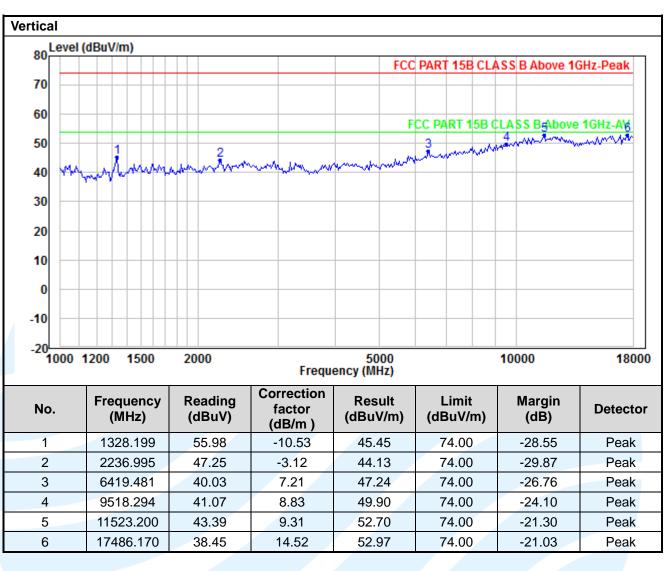












#### Remark:

- 1. Correct Factor = Antenna Factor + Cable Loss Amplifier Gain, the value was added to Original Receiver Reading by the software automatically.
- 2. Result = Reading + Correct Factor.
- 3. Margin = Result Limit
- 4. All possible modes of operation were investigated, and testing at two nominal voltages of 240V/50Hz and 120V/60Hz, only the worst case emissions reported.
- 5. For Radiated Emission above 18GHz, there was not any unwanted emission detected.
- 6. As shown in this section, for frequencies above 1GHz, the field strength limits are based on average limits. However, the peak field strength of any emission shall not exceed the maximum permitted average limits specified above by more than 20 dB under any condition of modulation. So, only the peak measurements were shown in the report.



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## **6.2 CONDUCTED EMISSION**

**Test Requirement:** FCC 47 CFR Part 15.107 ICES-003 Issue 6 Section 6.1

Test Method: ANSI C63.4-2014

Limits:

Limits for Class B devices

Frequency range	Limits (dB(μV)		
(MHz)	Quasi-peak	Average	
0,15 to 0,50	66 to 56	56 to 46	
0,50 to 5	56	46	
5 to 30	60	50	

#### Remark:

1. The lower limit shall apply at the transition frequencies.

2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 to 0.50 MHz.

**Test Setup:** Refer to section 4.3.2 for details.

#### **Test Procedures:**

- 1) The Product was placed on a nonconductive table 0.8 m above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- 2) The RBW of the receiver was set at 9 kHz in 150 kHz ~ 30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

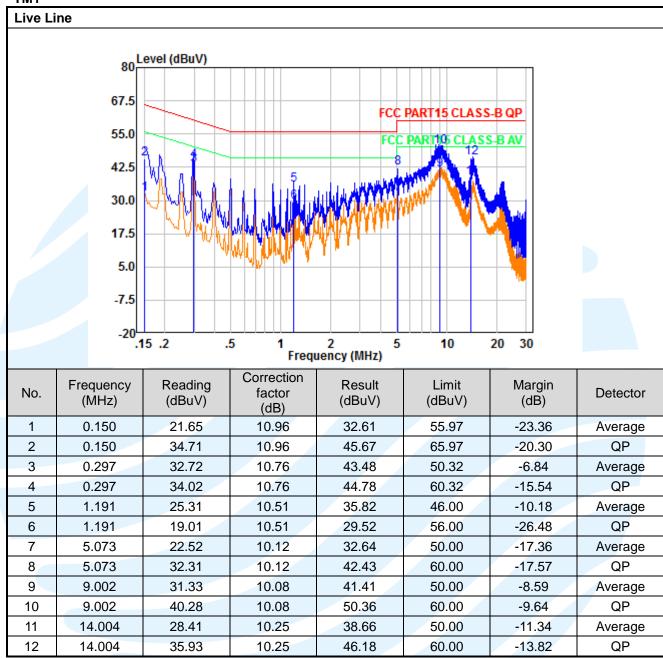
**Equipment Used:** Refer to section 3 for details.

Test Result: Pass

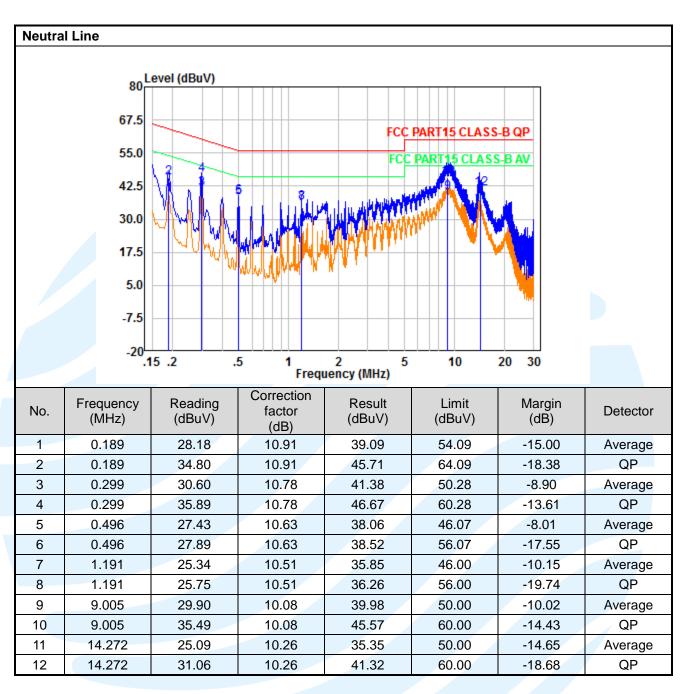


The measurement data as follows: Quasi Peak and Average:

TM1







#### Remark:

- 1. Correct Factor = LISN Factor + Cable Loss + Pulse Limiter Factor, the value was added to Original Receiver Reading by the software automatically.
- 2. Result = Reading + Correct Factor.
- Margin = Result Limit
- 4. An initial pre-scan was performed on the Phase and neutral lines with peak detector. Quasi-Peak and Average measurement were performed at the frequencies with maximized peak emission were detected.
- 5. All possible modes of operation were investigated, and testing at two nominal voltages of 240V/50Hz and 120V/60Hz, only the worst case emissions reported.

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## APPENDIX 1 PHOTOS OF TEST SETUP

See test photos attached in Appendix 1 for the actual connections between Product and support equipment.

## **APPENDIX 2 PHOTOS OF EUT CONSTRUCTIONAL DETAILS**

